U.S.N					

Max. Marks: 100

Time: 3 hrs

P.E.S. College of Engineering, Mandya - 571 401

(An Autonomous Institution affiliated to VTU, Belagavi)

Second Semester, M. Tech - VLSI Design and Embedded System (MECE) Semester End Examination; June - 2017 Design of VLSI Systems

Note: Answer *FIVE* full questions, selecting *ONE* full question from each unit. UNIT - I 1 a. Explain briefly the digital design domain and levels of abstraction with the help of Y chart. 6 b. What is hierarchy? Explain with a difference engine as an example. 6 c. With neat diagram, explain the Xilinx FPGA architecture and configurable logic blocks. 8 What is logic optimization? Explain with a typical flow diagram. 2 a. 10 Discuss different EDA tools which are used in VLSI design. b. 10 **UNIT - II** 3 a. Describe briefly the different design capture tools used in VLSI design. 12 b. Explain the following: 8 i) Network isomorphism ii) Layout extraction iii) Back annotation. 4 a. Draw a carry chain adder constructed using propagate, generate and kill signals. 6 b. With a necessary diagram, explain the Manchester adder with carry skip. 6 With the help of a neat diagram, explain the unsigned magnitude comparator. c. 8 UNIT - III 5 a. Explain how multiplication is performed using radix 4 booth encoding. 12 Explain array funnel shiffer with a neat diagram. b. 8 6 a. Explain the read and write operation with respect to SRAM. 8 b. Draw the basic ROM architecture using NOR array and explain its working. 8 Explain briefly quesues in memory. c. 4 **UNIT - IV** 7 a. Explain the FSM design procedure with an example. 10 b. What are the properties of I/O subsystem? 10 8 a. How global clock is generated? Explain if with respect to PLL. 10 List the properties of ideal power distribution network and explain IR drop and $\alpha \frac{di}{dt}$ noise. 10 b. UNIT - V Explain the following: 9 a. 10 i) Non recurring engineering costs ii) Recurring engineering costs iii) Fixed costs. b. With the help of a neat diagram, explain boundary scan architecture. 10 10. Write a short notes on: 20

iii) Observability and Controllability.

ii) Stuck at faults

i) Design for testability